

First call for papers

Goals

- To contribute to the recognition and development of Metrology as a relevant discipline for industry, commerce and science.
- To encourage communication and collaboration in Metrology.
- To disseminate the knowledge and experiences generated in CENAM, among calibration and testing laboratories, industry, research institutes and certification, inspection and standardization bodies.
- To enhance a culture of measurements in Mexico.

Who should attend

- Users of measurement systems
- Manufacturers, distributors and users of measurement equipment
- Technical and quality managers
- Metrologists
- Quality auditors
- Professors, researchers and students involved in metrology

Topics:

- **Industrial and Legal Metrology**
 - + Measurement related methods
 - + Instruments and measurement systems
 - + Traceability
 - + Estimation of uncertainty in measurements
 - + Validation of methods
 - + Accreditation of Calibration and Testing Laboratories
 - + Interlaboratory comparisons
 - + Use of reference materials
 - + Chemical measurements
 - + Environmental measurements
 - + Conformity assessment
 - + Standardization
- **Scientific Metrology**
 - + Primary Standards and high accuracy measurement systems
 - + New methods of measurement
 - + New standards of measurement
 - + Primary methods in analytical measurements
 - + International comparisons and mutual recognition agreements

Participation options

- **Attendee**
- **Author**
- **Sponsor**

Presentation options

- **Oral**
- **Poster**

Presentation

Deadline for abstracts: **March 31, 2004**

Acceptance of papers: **June 18, 2004**

Papers acceptance will be subjected to a Technical Committee evaluation

Abstracts:

- Extension: 100 to 200 words.
- Include full name, company, phone, fax and email details.
- Please send your submission to simposio@cenam.mx

Recovery Fee

- **Authors and attendees: US \$ 425**
Fee includes proceedings, certificate of attendance, 3 lunches, coffee breaks and one Banquet ticket
- **Sponsors: US \$ 1800** Space for exhibition of equipment
US \$ 720 Space for exhibition of commercial poster

Fee includes certificate of attendance, proceedings, 3 lunches, coffee breaks and one Banquet ticket (all for one person), and the inclusion of company logo on promotion material.

US \$ 220 for additional person (two additional at maximum)
- **Students: US \$ 160**
Fee includes: certificate of attendance, proceedings, 3 lunches, coffee breaks and one Banquet ticket
- **Fees are valid until July 31, 2004**

Additional Information / Organizing Committee

- **Erika Montaña Suárez:**
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- **Chairman: Roberto Arias Romero**
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PRE-REGISTRATION FORM SYMPOSIUM OF METROLOGY 2004

Send to:

Erika Montaña Suárez:
Organizing Committee

Phone: +52 (442) 211 05 00 al 04, ext. 3013

Direct: +52 (442) 211 05 83

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I wish to participate as:

Attendee

Author

Oral presentation

Poster

Topic: _____

Classification No.

See page 4 for classification scheme

Please attach copy of the abstract (oral presentation or poster)

Sponsor

With space for exhibition

With space for poster

My personal details are:

Name: _____

Company/Organization: _____

Address: _____

Zip/post code and city: _____

Country: _____

Telephone and Fax: _____

E-mail: _____

At your convenience, you will be informed on the procedures to complete your registration.

LIST OF TOPICS

- 1) Electromagnetic measurements**
 - a) DC voltage and current
 - b) Low frequency measurements
 - c) Radiofrequency and Microwaves
 - d) Magnetism
- 2) Time and frequency**
- 3) Temperature and Humidity**
 - a) Contact thermometry
 - b) Pyrometry
 - c) Humidity
 - d) Thermal conductivity and heat transfer
- 4) Optics and Radiometry**
 - a) Radiometry: detectors and sources
 - b) Photometry
 - c) Characterization of optical properties:
Spectrophotometry, colour, polarimetry, etc.
 - d) Fibre optics and optoelectronics
 - e) Holographic methods
- 5) Ionizing radiation**
- 6) Acoustic and vibration**
 - a) Acoustics
 - b) Vibration
- 7) Dimensional Measurements**
 - a) Primary standards and interferometry
 - b) Length and shape
 - c) Gage blocks, angle, roundness, etc.
 - d) Coordinate Measuring Machines
 - e) Roughness
- 8) Force and Pressure**
 - a) Force and Torque
 - b) Pressure and Vacuum
 - c) Hardness and Toughness
- 9) Mass and density**
 - a) Mass
 - b) Density
- 10) Volume and Flow**
 - a) Liquid flow-rate
 - b) Gas flow-rate
 - c) Calibration of glassware
 - d) Calibration of large vessels
- 11) Viscosity and Rheology**
- 12) Metrology in Chemistry**
 - a) Primary methods
 - b) Gas metrology
 - c) Purity measurements
- 13) Reference Materials**
 - a) Solutions
 - b) Simple matrix
 - c) Complex matrix
 - d) Development of reference materials
- 14) Reference Materials applications**
 - a) Food
 - b) Biometrology
 - c) Environment
 - d) Geochemistry and ors
 - e) Raw materials
 - f) Metallurgy
 - g) Gas mixtures
 - h) Agriculture
- 15) Uncertainty in Measurements**
- 16) Statistic Process Control**
- 17) Validation of methods**
- 18) Quality Systems**
- 19) Standardization**
- 20) Accreditation**
- 21) Comparison and Proficiency testing**
- 22) Automation of Measuring Systems**
- 23) Image processing**
- 24) Legal Metrology and pattern approval of Measuring instruments**
- 25) Training in Metrology**
- 26) General Topics in Metrology**